SN54ABT162240, SN74ABT162240 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS SCB5237 – JUNE 1992 – REVISED OCTOBER 1992

SN54ABT162240 . . . WD PACKAGE • Output Ports Have Equivalent 25-Ω Series SN74ABT162240 . . . DL PACKAGE **Resistors, So No External Resistors Are** (TOP VIEW) Required **Members of the Texas Instruments** 1 OE 48 20E Widebus[™] Family 1Y1 2 47 **1**A1 • State-of-the-Art EPIC-IIB ™ BiCMOS Design 1Y2 3 46 1A2 **Significantly Reduces Power Dissipation** GND 4 45 GND Latch-Up Performance Exceeds 500 mA 1Y3 5 44 1A3 Per JEDEC Standard JESD-17 1Y4 6 43 🛛 1A4 V_{CC} [] 7 42 VCC Typical V_{OLP} (Output Ground Bounce) 2Y1 8 41 2A1 < 1 V at V_{CC} = 5 V, T_A = 25°C 2Y2 9 40 2A2 Distributed V_{CC} and GND Pin Configuration GND 10 39 GND **Minimizes High-Speed Switching Noise** 2Y3 11 38 2A3 Flow-Through Architecture Optimizes 37 🛛 2A4 2Y4 12 **PCB Lavout** 36 **3**A1 3Y1 13 Packaged in Plastic 300-mil Shrink 3Y2 14 35 3A2 Small-Outline Packages and 380-mil GND [] 15 34 GND Fine-Pitch Ceramic Flat Packages Using 3Y3 16 33 🛛 3A3 25-mil Center-to-Center Spacings 3Y4 1 17 32 3A4 V_{CC} 18 31 V_{CC} description 4Y1 19 30 4A1 4Y2 20 29 4A2 The 'ABT162240 is a 16-bit buffer and line driver GND 21 28 GND designed specifically to improve both the 4Y3 22 27 4A3 performance and density of 3-state memory 4Y4 23 26 🛛 4A4

performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. This device provides inverting outputs and symmetrical \overline{OE} (active-low output-enable) inputs.

The outputs, which are designed to source or sink up to 12 mA, include $25 \cdot \Omega$ series resistors to reduce overshoot and undershoot.

4<u>OE</u> 24

25 30E

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ABT162240 is available in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ABT162240 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ABT162240 is characterized for operation from -40° C to 85° C.

FUNCTION TABLE	
(each 4-bit buffer)	

INP	JTS	OUTPUT
OE	Α	Y
L	Н	L
L	L	н
Н	Х	Z

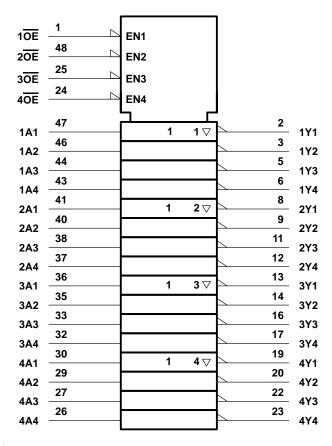
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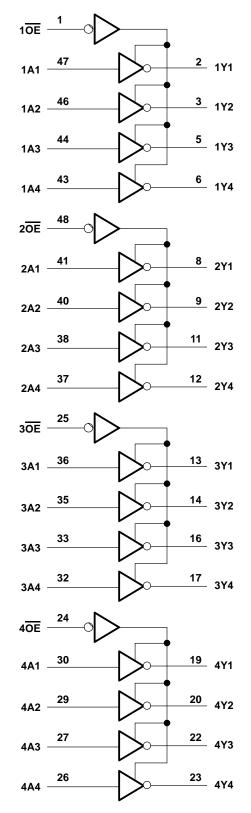
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1)	
Voltage range applied to any output in the high state or power-off state, V_{O}	
Current into any output in the low state, I _O	
Input clamp current, I_{IK} (V _I < 0)	
Output clamp current, I_{OK} (V _O < 0)	
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air)	
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions (see Note 2)

					SN74ABT162240		UNIT
		MIN	MAX	MIN	MAX	UNIT	
VCC	Supply voltage	4.5	5.5	4.5	5.5	V	
VIH	High-level input voltage	2		2		V	
VIL	Low-level input voltage			0.8		0.8	V
VI	Input voltage			Vcc	0	VCC	V
ЮН	High-level output current			-12		-12	mA
IOL	Low-level output current			12		12	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
TA	Operating free-air temperature			125	-40	85	°C

NOTE 2: Unused or floating inputs must be held high or low.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS			T _A = 25°C			SN54ABT162240		SN74AB	T162240		
PARAMETER				MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT	
VIK	$V_{CC} = 4.5 V$, $I_{I} = -18 mA$					-1.2		-1.2		-1.2	V	
	$V_{CC} = 4.5 \text{ V}, I_{OH} = -1 \text{ mA}$			3.35			3.3		3.35			
Mari	V _{CC} = 5 V,	I _{OH} = – 1 mA					3.8		3.85			
VOH	V _{CC} = 4.5 V,	$I_{\rm OH} = -3 \rm mA$		3.1			3		3.1		v	
	$V_{CC} = 4.5 \text{ V}, I_{OH} = -12 \text{ mA}$			2.6‡					2.6			
VOL	$V_{CC} = 4.5 V,$ $I_{OL} = 8 mA$ $V_{CC} = 4.5 V,$ $I_{OL} = 12 mA$				0.4	0.8		0.8		0.65	V	
VOL										0.8	V	
lj	$V_{CC} = 5.5 \text{ V}, V_{I} = V_{CC} \text{ or GND}$					±1		±1		±1	μA	
IOZH	$V_{CC} = 5.5 \text{ V}, V_{O} = 2.7 \text{ V}$					50		50		50	μA	
IOZL	$V_{CC} = 5.5 \text{ V}, V_{O} = 0.5 \text{ V}$					-50		-50		-50	μΑ	
l _{off}	V _{CC} = 0,	$_{\rm C} = 0,$ $V_{\rm I} \text{ or } V_{\rm O} \le 4.5 \text{ V}$				±100				±100	μA	
ICEX	V _{CC} = 5.5 V,	V _O = 5.5 V	Outputs high			50		50		50	μA	
۱ ₀ §	V _{CC} = 5.5 V,	V _O = 2.5 V		-50	-100	-180	-50	-180	-50	-180	mA	
			Outputs high			2		2		2		
ICC	$V_{CC} = 5.5 \text{ V}, I_O = 0,$ $V_I = V_{CC} \text{ or GND}$		Outputs low			32		32		32	mA	
			Outputs disabled			2		2		2		
	3.4 V, Other inputs	One input at	Data inputs	Outputs enabled			1		1.5		1	
ΔI_{CC}		· ·	Outputs disabled			0.05		1		0.05	mA	
	at V _{CC} or GND Control inputs		3			1.5		1.5		1.5		
Ci	VI = 2.5 V or 0.5 V				7						pF	
Co	V _O = 2.5 V or 0.5 V				7						pF	

† All typical values are at $V_{CC} = 5$ V.

[‡] On products compliant to MIL-STD-883, Class B, this parameter does not apply.

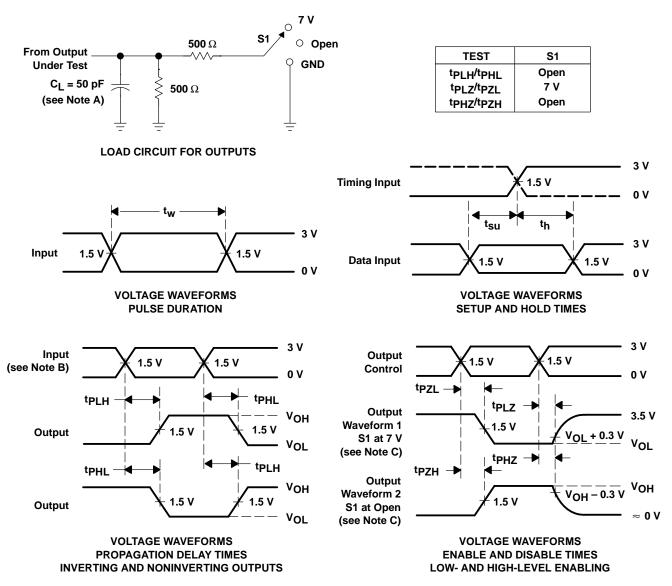
§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 \P This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_Q = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.

C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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